## Search Notes

| Application/Control No. | Applicant(s)/Patent Under Reexamination |
|-------------------------|---|
| 10550102                | YOKOTAGAWA ET AL.                       |
| Examiner                | Art Unit                                |
| Niebauer, Ronald T      | 1654                                    |

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| SEARCHED |          |        |          |  |  |
|----------|----------|--------|----------|--|--|
| Class    | Subclass | Date   | Examiner |  |  |
| NONE     |          | 2/6/08 | rtn      |  |  |

| SEARCH NOTES  |         |          |  |  |  |
|---|---------|----------|--|--|--|
| Search Notes  | Date    | Examiner |  |  |  |
| Inventor search in EAST, eDAN; STIC search on SEQ ID NO:1 (results in eDAN) | 4/16/07 | rtn      |  |  |  |
| PubMed, EAST search   | 4/16/07 | rtn      |  |  |  |
| STN search (reg,caplus,biosis,medline) - see enclosed                       | 9/5/07  | rtn      |  |  |  |
| updated inventor search in PALM, EAST                                       | 9/5/07  | rtn      |  |  |  |
| EAST search (uspat, uspgpub,osocr,fprs,epo,jpo,derwent) - see enclosed      | 9/5/07  | rtn      |  |  |  |
| EAST search and interference search   | 2/6/08  | rtn      |  |  |  |
| (uspat,uspgpub,usocr,fprs,epo,jpo,derwent) - see enclosed                   |         |          |  |  |  |
| updated STN search (reg,caplus,biosis,embase) - see enclosed                | 2/6/08  | rtn      |  |  |  |
| STIC sequence search - see SCORE content                                    | 2/6/08  | rtn      |  |  |  |

| INTERFERENCE SEARCH |                 |          |        |          |  |
|---------------------|-----------------|----------|--------|----------|--|
| Class               |                 | Subclass | Date   | Examiner |  |
|                     | see notes above |          | 2/6/08 | rtn      |  |

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